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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of

Yoshiharu KOBAYASHI et al. : Mail Stop: PCT  
Serial No. 10/560,810 : Attorney Docket No. 2005\_1750A  
Filed December 15, 2005 :

OPTICAL DISK APPARATUS AND  
OPTICAL DISK  
[Corresponding to PCT/JP2004/018578  
Filed December 13, 2004]

**INFORMATION DISCLOSURE STATEMENT**

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

THE COMMISSIONER IS AUTHORIZED  
TO CHARGE ANY DEFICIENCY IN THE  
FEES FOR THIS PAPER TO DEPOSIT  
ACCOUNT NO. 23-0975

Sir:

Pursuant to the provisions of 37 CFR 1.56, 1.97 and 1.98, Applicants request consideration of the references listed on attached form PTO-1449 and any additional information identified below in paragraph 3. A legible copy of each reference listed on the Form PTO-1449 is enclosed, except a copy is not provided for:

- each U.S. Patent and U.S. Patent application publication;
- each reference previously cited in the international application PCT/\_\_\_\_\_ ; and/or
- each reference previously cited in prior parent application Serial No. \_\_\_\_\_.

1a.  This Information Disclosure Statement is submitted:

within three months of the filing date (or of entry into the National Stage) of the above-entitled application, or

before the mailing of a first Office Action on the merits or the mailing of a first Office Action after the filing of an RCE,

**and thus no certification and/or fee is required.**

1b.  This Information Disclosure Statement is submitted

after the events of above paragraph 1a and prior to the mailing date of a final Office Action or a Notice of Allowance or an action which otherwise closes prosecution in the application, and thus:

(1)  the certification of paragraph 2 below is provided, **or**

(2)  the fee of \$180.00 specified in 37 CFR 1.17(p) is enclosed.

1c.  This Information Disclosure Statement is submitted:

after the mailing date of a final Office Action or Notice of Allowance or action which otherwise closes prosecution in the application, and prior to payment of the issue fee, and thus:

**the certification of paragraph 2 below is provided, and**

**the fee of \$180.00 specified in 37 CFR 1.17(p) is enclosed.**

2. It is hereby certified

- a.  that each item of information contained in this Information Disclosure Statement was first cited in any communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of the Statement, or
- b.  that no item of information contained in the Information Disclosure Statement was cited in a communication from a foreign patent office in a counterpart foreign application and, to the knowledge of the person signing the certification after making reasonable inquiry, was known to any individual designated in §1.56(c) more than three months prior to the filing of the Statement.

3.  Consideration of the following list of additional information (including any copending or abandoned U.S. application, prior uses and/or sales, etc.) is requested.

4. For each non-English language reference listed on the attached form PTO-1449, reference is made to:

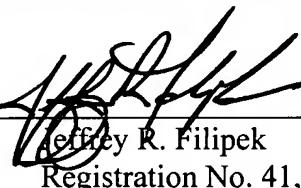
- a full or partial English language translation submitted herewith,
- a foreign patent office search report (in the English language) submitted herewith,
- the concise explanation contained in the specification of the present application at pages 2, 3, 10, 14, and 23,
- the concise explanation set forth in the attached English language abstract,
- the concise explanation set forth below or on a separate sheet attached to the reference:

5.  A foreign patent office search report citing one or more of the references is enclosed.

Respectfully submitted,

Yoshiharu KOBAYASHI et al.

By



\_\_\_\_\_  
Jeffrey R. Filipek  
Registration No. 41,471  
Attorney for Applicants

JRF/fs  
Washington, D.C. 20006-1021  
Telephone (202) 721-8200  
Facsimile (202) 721-8250  
February 16, 2006

## INFORMATION DISCLOSURE STATEMENT

FORM PTO 1449 (modified)

ATTY DOCKET NO.  
2005\_1750ASERIAL NO.  
10/560,810U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICELIST OF REFERENCES CITED BY APPLICANT(S)  
(Use several sheets if necessary)

Date Submitted to PTO: February 16, 2006

APPLICANT  
Yoshiharu KOBAYASHI et al.FILING DATE  
December 15, 2005O I P E  
FEB 16 2006  
U. S. PATENT & TRADEMARK OFFICE

GROUP

## U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA	5,289,407	2-22-94	Strickler et al.			
	AB						
	AC						

## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
	AD	11-232677	8-27-99	Japan			abstract
	AE	2003-77158	3-14-03	Japan			abstract
	AF	2003-16680	1-17-03	Japan			abstract
	AG						
	AH						

## OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)

	AI	3.2 Disk Design Technology, Matsushita Technical Journal, Vol. 45, No. 6, December 1999, pages 672-678 (along with abstract)
	AJ	M. Miyamoto et al., "Analysis to reduce cross erase for phase-change optical disks", The Institute of Electronics, Information and Communication Engineers, Technical Report of IEICE.CPM2000-95 (2000-09), pages 21-27 (along with abstract)
	AK	Mark A. A. Neil et al., "New modal wave-front sensor: a theoretical analysis", J. Opt. Soc. Am. A/Vol. 17, No. 6/ June 2000, pages 1098-1107
	AL	Carlos Robledo-Sánchez et al., "Aberration extraction in the Hartmann test by use of spatial filters", Applied Optics, Vol. 38, No. 16, June 1, 1999, pages 3483-3489
	AM	M. A. A. Neil et al., "Closed-loop aberration correction by use of a modal Zernike wave-front sensor", Optics Letters, August 1, 2000, Vol. 25, No. 15, pages 1083-1085
	AN	Mark A. A. Neil et al., "Active aberration correction for the writing of three-dimensional optical memory devices", Applied Optics, Vol. 41, No. 7, March 1, 2002, pages 1374-1379

EXAMINER

DATE CONSIDERED